


<b>Search Notes</b>  	<b>Application/Control No.</b>  10560758	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER ET AL.
	<b>Examiner</b>  JAEYUN LEE	<b>Art Unit</b>  1791

SEARCHED			
Class	Subclass	Date	Examiner
156	105, 106, 107	7/29/2009	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
East search (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, Derwent, IBM TDB) and text search	7/22/2009	/JL/
Consulted Primary Examiner (Jeff Aftergut)	7/22/2009	/JL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/JAEYUN LEE/  
Examiner,Art Unit 1791